

Search Notes

Application/Control No.

09/194,164

Examiner

Christopher H. Yaen

Applicant(s)/Patent under
Reexamination

DAN ET AL.

Art Unit

1642

SEARCHED

Class	Subclass	Date	Examiner
updated		5/13/2005	CHY

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
536	23.1	5/13/2005	CHY
530	387.1	5/13/2005	CHY
stic SEQ ID No: 13,14			

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated searches	5/13/2005	CHY
Plam Inventor search	5/13/2005	CHY
stic interference search SEQ ID No: 13, 14	5/13/2005	CHY
Patent conf: J. Siew and J. Housel	4/28/2005	CHY